## Recent advances in Complexity CIS 6930/CIS 4930

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## Lecture 21

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Our main goal is to prove Nisan-Wigderson theorem (1988), which relates hardness to pseudorandomness.

## Theorem 1 (Nisan and Wigderson, 1988)

For every s, where  $l \leq s(l) \leq 2^l$ , the following are equivalent:

- (1) For some c > 0,  $\exists$  some function  $f_n$  in EXPTIME that cannot be approximated by circuits of size  $s(l^c)$ .
- (2) For some c > 0,  $\exists a \ f_n \ in \ EXPTIME \ with \ hardness \ s(l^c)$ .
- (3) For some c > 0,  $\exists$  a  $DTIME(2^l)$  pseudorandom generator  $G: l \longrightarrow s(l^c)$ , such that  $\forall$  circuit C of size  $s(l^c) = n$ ,

$$|P[C(y) = 1] - P[C(G(x)) = 1]| \le \frac{1}{s(l^c)},$$

(21.1)

where y is uniformly distributed on  $\{0,1\}^n$  and x is uniformly distributed on  $\{0,1\}^l$ .

## Corollary

 $RAC^0 \subseteq DSPACE(poly/log(n)) \subseteq DTIME(2^{poly/log(n)}) = DTIME(n^{poly/log(n)}) \subseteq constant depth polynomiae size circuits,$ 

where  $RAC^0$  is Randomized  $AC^0$ , or randomized constant depth polynomial size circuits. A circuit C in  $RAC^0$  takes I as regular input and x as random inputs. If  $I \in S$ , then C(I,x)=1 with probability  $\geq \frac{1}{2}+\epsilon$  and if  $I \notin S$ , then C(I,x)=0 with probability  $\geq \frac{1}{2}+\epsilon$ .

Note to find 1 bit that looks random to circuit of size  $s(m^c)$  we can simply take the output of f. It is a problem to come up with lots of bits. To get a pseudo random generator from f to satisfy condition c1 we need the XOR Lemma. First we give some definitions.

**Definition 1** Given a Boolean function  $f_n: \{0,1\}^n \longrightarrow \{0,1\}$ , we say  $f_n$  is  $(\gamma,s)$  hard if for any circuit of size s

$$|P[C(x) = f(x)] - \frac{1}{2}| < \frac{\gamma}{2}$$

$$|P[C(x) \neq f(x)]| \ge \frac{1}{2} - \frac{\gamma}{2}$$

where  $0 < \gamma < 1$ .

**Definition 2** We say that f cannot be approximated by circuit of size s(n) if for some constant k, all large enough n and circuits  $C_n$  of size s(n):

$$Prob[C_n(x) \neq f(x)] > \frac{1}{n^k}$$

where x is chosen uniformly in  $\{0,1\}$ .

**Definition 3** Let  $f: \{0,1\}^n \longrightarrow \{0,1\}$  be a Boolean function uniformly defined and let  $f_m$  be restrictions of f to strings of length m. The hardness of f at m  $H_f(m)$  is the maximum integer  $h_m$  such that f is  $(1/h_m, h_m)$  - hard.

Notice this is pretty much the same as the hardness definition given in Erwin's talk.

Lemma 2 (Hardness amplification, Yao's XOR Lemma)

Let  $f_1, ..., f_k$  be all  $(\gamma, s)$  hard. Then for any  $\mu > 0$  the function  $f(x_1, ..., x_k) = \sum_{i=1}^k f_i(x_i) mod 2$  is  $(\gamma + \mu, \mu^2 (1 - \gamma)^2 s)$ -hard, where  $x_i$ 's are all strings.

Idea The output of G is a sequence of bits, where each bit is  $f(x_i)$ , where  $x_i$  is a small seed. We want to choose  $x_i$ 's such that the  $x_i$ 's are not highly correlated. Intuitively, choose  $x_i, x_j$  in the set such that  $|x_i \cap x_j|$  is small.

**Definition 4** A collection  $\{S_1,...,S_n\}$  of sets where  $S_i \subseteq \{1,...,l\}$  is called a (k,m) design, if  $\forall i$ ,

- (1)  $|S_i| = m$ , (each  $x_i$  does not have too many 1's)
- (2)  $\forall i \neq j | S_i \cap S_j | \leq k$ .

Our pseudo random generator G takes a seed x of length l. The  $x_i$ 's are chosen as a (k,m) design on the set of 1-bits of x.  $G(x) = f(x_1)f(x_2)...f(x_n)$ . Recall  $n = s(l^c)$  in the statement of the theorem.

**Lemma 3** Let m, n, l be integers.  $f: \{0, 1\}^m \longrightarrow \{0, 1\}$ .  $H_f(m) \ge n^2$  and let A be a Boolean  $n \times l$  matrix which is a (logn, m) design. Then  $G: \{0, 1\}^l \longrightarrow \{0, 1\}^n$  given as above is a pseudo random generator satisfying (21.1) in the statement of the main theorem.